

**Search Notes**

Application/Control No.

10/679,290

Examiner

ALEX LIEW

Applicant(s)/Patent under  
Reexamination

SHISHIDO ET AL.

Art Unit

2624

**SEARCHED**

Class	Subclass	Date	Examiner
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**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
Interference search		9/13/2008	AL

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
382/141-152, 154 limited to text search	9/13/2008	AL
Inventor name search	9/13/2008	AL
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